


<b>Search Notes</b>  	<b>Application/Control No.</b>  10533640	<b>Applicant(s)/Patent Under Reexamination</b>  YACHIA ET AL.
	<b>Examiner</b>  John P Lacyk	<b>Art Unit</b>  3735

SEARCHED			
Class	Subclass	Date	Examiner
600	29-32	9/28/08	JPL
128	Dig 25, 899	9/28/08	JPL

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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